

SAWG

(Surface and Micro/Nano Analysis Working Group)

Measurands:

- Composition of films (0.5 nm to 50 ... 100 μm) in [mol/mol] – K67, 129
- Amount of substance expressed as a layer thickness in [nm] – K32
- Specific Surface area (BET) in [m^2/g] and related parameters derived from adsorption isotherms – K136
- 2D and 3D spatially resolved chemical composition (elemental and phases) in the future

Customers: Analytical laboratories in the industry:

semiconductors, transportation, telecom, sensing, medical devices, oil and gas,...

SAWG: Portfolio of methods

Traceable methods	Methods not traceable but highly relevant for customers (industry)
XRR: PTB at BESSY II, NMIJ & NIM (laboratory) UHV	Photoelectron and Augerelectron Spectroscopy (XPS, AES) UHV
Neutron reflectometry: NIST HV	Secondary Ion Mass Spectrometry (SIMS) UHV
XRF: PTB at BESSY II UHV	Electron probe micro analysis (EPMA) HV
ID - ICP MS: KRISS, NIM, NIST, BAM, NMIJ, UNIIM, CENAM	Total reflection X-ray Fluorescence Spectroscopy XRF ambient ... UHV
HR TEM, STEM: KRISS, NMIJ, NIM, NIST UHV	Ellipsometry ambient
	Optical methods: Infrared and Raman Spectroscopy ambient
	Specific surface area measurement (BET surface and related parameters as pore diameter) Methods operationally defined; NMIs provide the highest level of reference for this measurements.

Approach: Use traceable methods to calibrate relevant field methods (using CRMs, film thickness to determine e.g. effective attenuation lengths for XPS (K 32), sputter rates, ...)

SAWG: Achievements and challenges

- *Major Achievement for WG in last period?*
 - KC on CIGS solar cell material,
 - KC on BET specific surface area of alumina powder
- *Major Challenges for WG in last period?*
 - traceability issues,
 - cross disciplinary character
- *Major Challenges for WG in the future period?*
 - establishment of traceability routes for industrially relevant methods for surface chemical analysis*
 - implementation of core competencies and related broader CMC claims
- *Number of comparisons per year for future period?*
 - 1 - 2 per year

*Responsibility of SAWG (strategy doc):

(2) To identify and carry out **inter-laboratory work** and **pilot studies** required to underpin the development of **reference measurement systems** in the field of spatially resolved chemical surface analysis at the micro and nanoscale, of the **highest possible metrological order with traceability to the SI**, where feasible, or to **other internationally agreed units**, to support **NMI/DI measurement services being developed in response to customer needs**.